



Vanta Element™ XRF Analyzer Series

Affordable Alloy ID and Light Element Analysis

Affordable, Rugged, and Connected

The Vanta Element handheld XRF analyzer series provides elemental analysis for fast alloy grade identification and sorting at an affordable price. The series is available in two cost-effective models:

- **Vanta Element** analyzer for affordable alloy ID
- **Vanta Element-S** analyzer for affordable alloy ID, including light element detection for magnesium (Mg), aluminum (Al), silicon (Si), sulfur (S), and phosphorus (P)

Easy to operate, both models feature fast grade ID and clear on-screen grade comparison to speed up metal testing for scrap sorting, metal manufacturing, and precious metals analysis.

The analyzer's smartphone-like user interface helps increase efficiency and throughput with features like on-screen grade comparison, sorting instructions, and identifying contaminants or the presence of residual elements that can compromise value and quality. Easy to use and easy to learn, the software helps reduce user training and streamlines the sorting process.

Confidently Verify and Sort Metals and Alloys

The Vanta Element series includes an alloy database with the most commonly used alloys in scrap recycling and manufacturing. Easily customize the database for proprietary or additional grades.

- Low-alloy steels: Fe | Mn | Cu
- Copper alloys: Cu | Zn | Sn
- Aluminum alloys: Mg | Al | Si
- Stainless steel: Fe | Cr | Ni | Mo
- Nickel alloys: Ni | Co | Fe
- Precious metals: Au | Ag | Pt | Pd



Modern

The Vanta Element™ series includes connectivity features to help streamline your quality control process.

Powerful Processing

- Fast and accurate Vanta™ electronics
- Axon Technology™ stability and count rate

Convenient Data Management

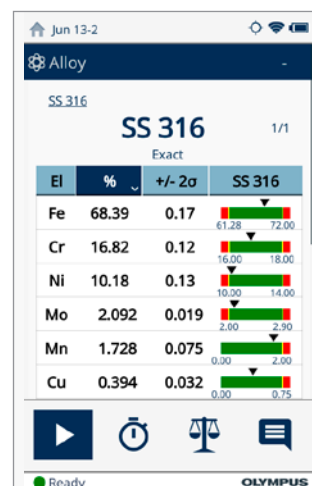
- Direct export to a USB drive
- 1 GB microSD™ card for storing results
- Wireless data transfer to a network folder (optional)
- Cloud data storage and real-time remote data viewing using the Olympus Scientific Cloud™

	Vanta Element Model	Vanta Element-S Model
Use	Affordable alloy ID	Affordable light element detection
Best for	Fast, basic analysis	Analyzing Mg, Al, Si, S, and P
Detector	PIN	Silicon drift detector (SDD)
Window	Thick Kapton window	Prolene window with Kapton mesh support
Excitation Source	2-watt X-ray tube with 35 kV tungsten (W) anode	4-watt X-ray tube with 50 kV silver (Ag) anode

Rugged and Affordable

Built for harsh and demanding environments, the Vanta Element series delivers a lower cost of ownership:

- IP54 rated for protection against dust and moisture
- Drop tested (MIL-STD-810G) to protect against falls and reduce the need for costly repairs
- Rated for continuous testing from -10 °C to 45 °C (14 °F to 113 °F)
- Stainless steel faceplate for wear protection
- Easy, toolless window replacement
- Industry-leading 3-year comprehensive warranty



Clear on-screen grade comparison.

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VantaElement_S_BR_Letter_2021_01 PN.920-634• Printed in the USA

